

**Notic of References Cited**

Application/Control No.

10/040,797

Applicant(s)/Patent Under  
Reexamination  
GOLDFINE ET AL.

Examiner

Jeffrey R. West

Art Unit

2857

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,453,689	09-1995	Goldfine et al.	324/239
	B	US-5,394,084	02-1995	Snyder	324/225
	C	US-5,223,796	06-1993	Waldman et al.	324/687
	D	US-5,426,373	06-1995	Diamond et al.	324/663
	E	US-5,059,902	10-1991	Linder	324/207.17
	F	US-4,814,690	03-1989	Melcher et al.	324/674
	G	US-5,654,643	08-1997	Bechtel et al.	324/687
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zaretsky et al., "Continuum Properties from Interdigital Electrode Dielectrometry", IEEE Transactions on Electrical Insulation. Vol 23, No. 6. 12-1988.
	V	Sadiku, "Elements of Electromagnetics", Oxford University Press. pp 289-290 1995.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.